Feathers:

- Advanced trench process technology
- avalanche energy, 100% test
- Fully characterized avalanche voltage and current

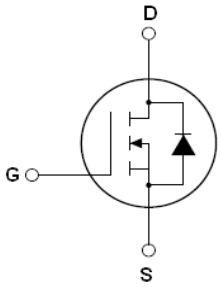
Description:

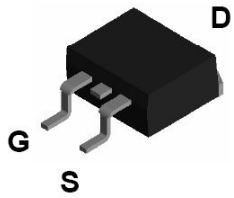
The SSF1016D is a new generation of high voltage and low current N–Channel enhancement mode trench power MOSFET. This new technology increases the device reliability and electrical parameter repeatability. SSF1016D is assembled in high reliability and qualified assembly house.

Application:

- Power switching application

ID =60A
BV=100V
Rdson=16mΩ (Max.)





SSF1016D TOP View (DPAK)

Absolute Maximum Ratings

	Parameter	Max.	Units
I_D@T_c=25℃	Continuous drain current,VGS@10V	60	A
I_D@T_c=100℃	Continuous drain current,VGS@10V	50	
I_{DM}	Pulsed drain current ①	240	
P_D@T_C=25℃	Power dissipation	144	W
	Linear derating factor	1.5	W/℃
V_{GS}	Gate-to-Source voltage	±20	V
E_{AS}	Single pulse avalanche energy ②	380	mJ
dv/dt	Peak diode recovery voltage	31	v/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	–55 to +175	℃

Thermal Resistance

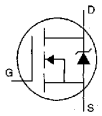
	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case	—	0.52	—	℃/W
$R_{\theta JA}$	Junction-to-ambient	—	—	62	

Electrical Characteristics @TJ=25℃ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain-to-Source breakdown voltage	100	—	—	V	V_{GS}=0V,I_D=250μA
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	11	16	mΩ	V_{GS}=10V,I_D=30A
$V_{GS(th)}$	Gate threshold voltage	2.0	—	4.0	V	V_{DS}=V_{GS},I_D=250μA
I_{DSS}	Drain-to-Source leakage current	—	—	2	μA	V_{DS}=100V,V_{GS}=0V
		—	—	10		V_{DS}=100V, V_{GS}=0V,T_J=150℃
I_{GSS}	Gate-to-Source forward leakage	—	—	100	nA	V_{GS}=20V
	Gate-to-Source reverse leakage	—	—	-100		V_{GS}=-20V
Q_g	*Total gate charge*	—	90		nC	

Q_{gs}	*Gate-to-Source charge*	—	20	—		I_D=30A,V_{GS}=10V V_{DD}=30V
Q_{gd}	*Gate-to-Drain("Miller") charge*	—	31	—		
$t_{d(on)}$	*Turn-on delay time*	—	18.2		nS	V_{DD}=30V I_D=2A ,R_L=15Ω R_G=2.5Ω V_{GS}=10V
t_r	*Rise time*	—	15.6			
$t_{d(off)}$	*Turn-Off delay time*	—	70.5			
t_f	*Fall time*	—	13.8			
C_{iss}	*Input capacitance*	—	3150		pF	V_{GS}=0V V_{DS}=25V f=1.0MHZ
C_{oss}	Output capacitance	—	350			
C_{rss}	Reverse transfer capacitance	—	240			

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I_S	Continuous Source Current (Body Diode)	—	—	75	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	300		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	T_J=25℃,I_S=60A,V_{GS}=0V ③
t_{rr}	Reverse Recovery Time	—	57	—	nS	T_J=25℃,I_F=75A di/dt=100A/μs ③
Q_{rr}	Reverse Recovery Charge	—	107	—	μC	
t_{on}	Forward Turn-on Time	Intrinsic turn-on time is negligible (turn-on is dominated by Ls + LD)				

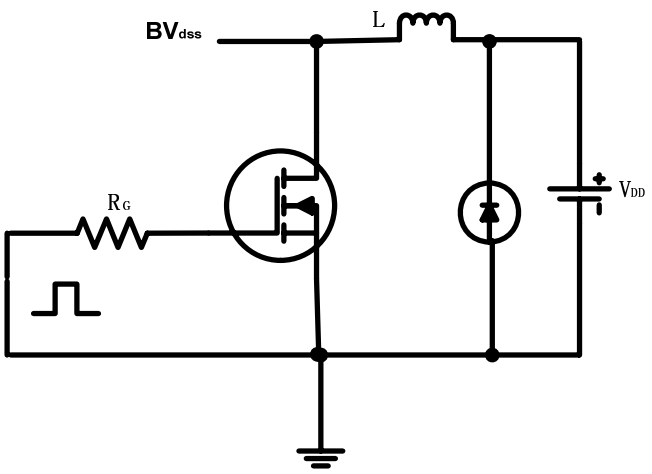
Notes:

① Repetitive rating; pulse width limited by max junction temperature.

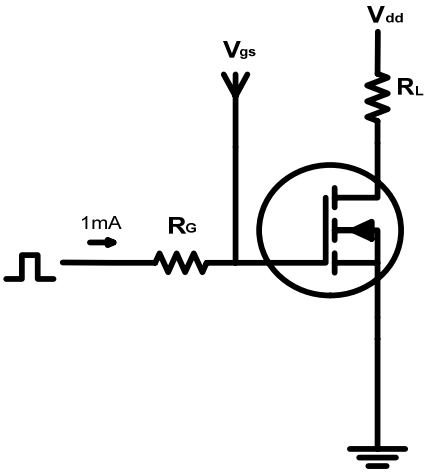
② Test condition: L =0.3mH, VDD = 50V,Id=37A

③ Pulse width≤300μS, duty cycle≤1.5% ; RG = 25Ω Starting TJ = 25°C

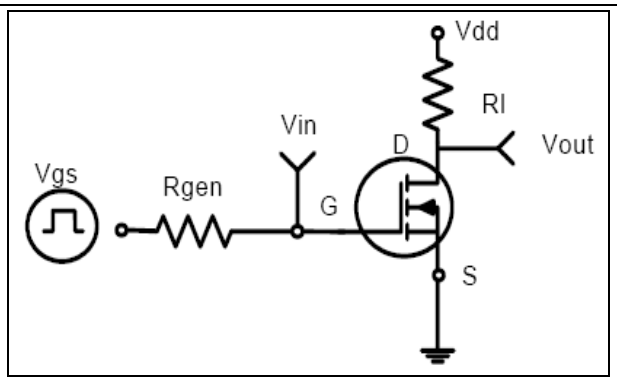
EAS Test Circuit:

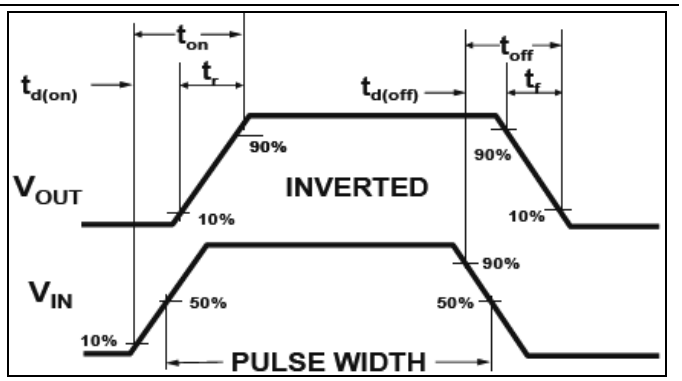


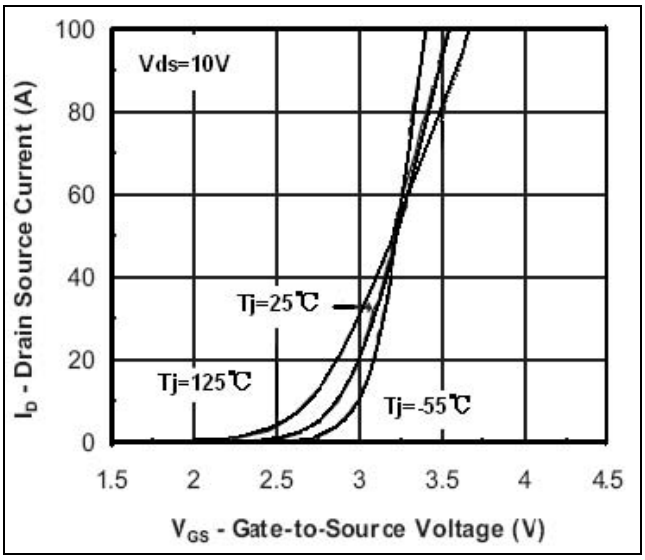
Gate Charge Test Circuit:



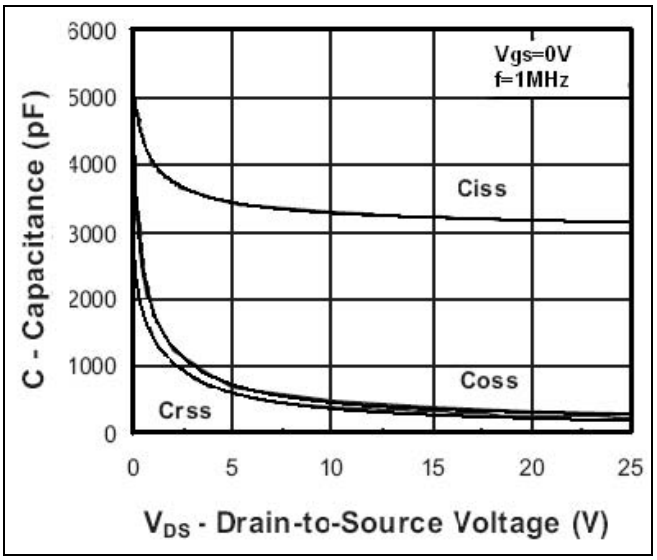
Switch Time Test Circuit: **Switch Waveform:**



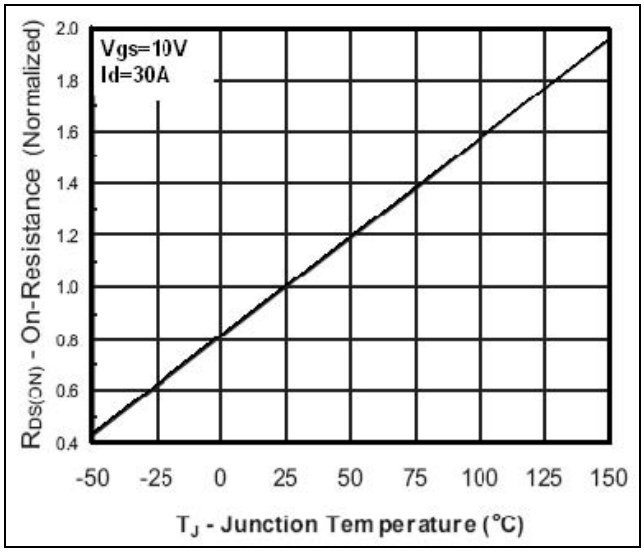




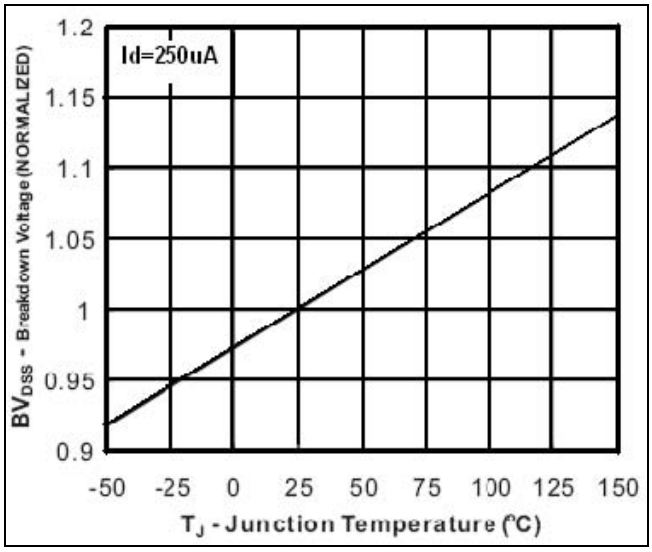
Transfer Characteristic



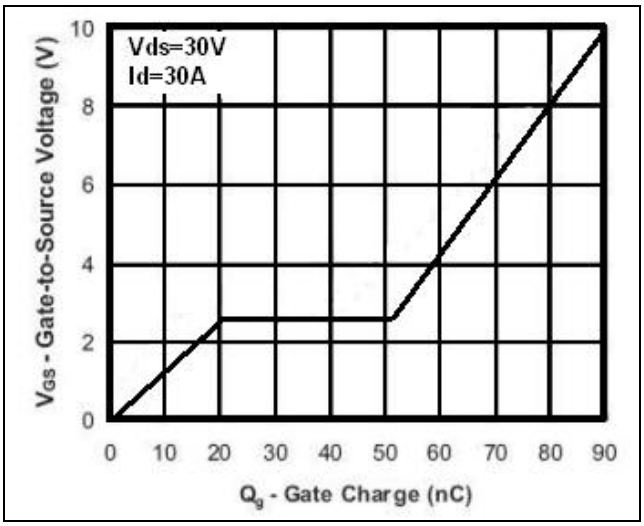
Capacitance



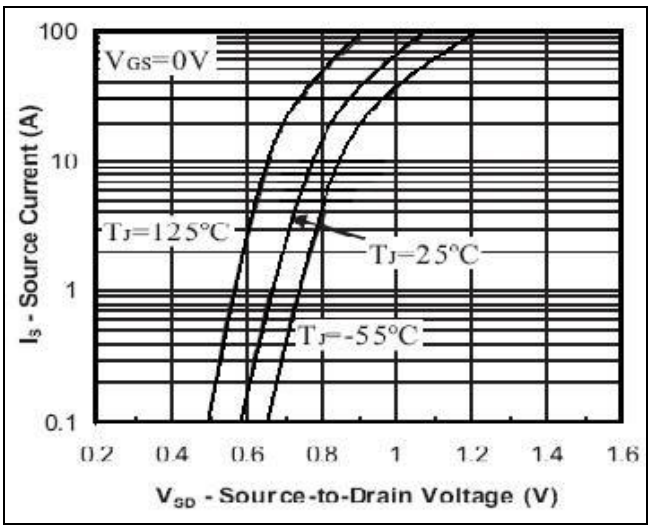
On Resistance vs. Junction Temperature



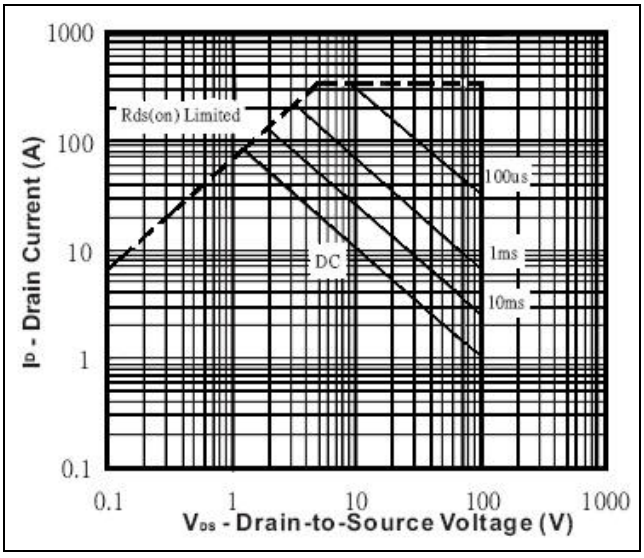
Breakdown Voltage vs. Junction Temperature



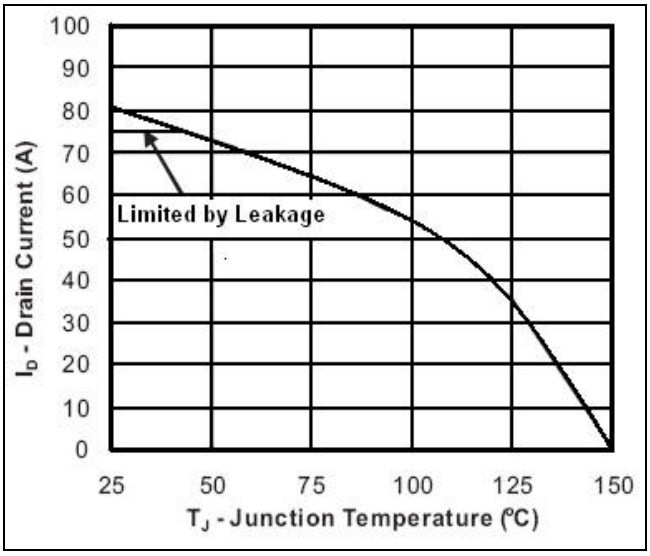
Gate Charge



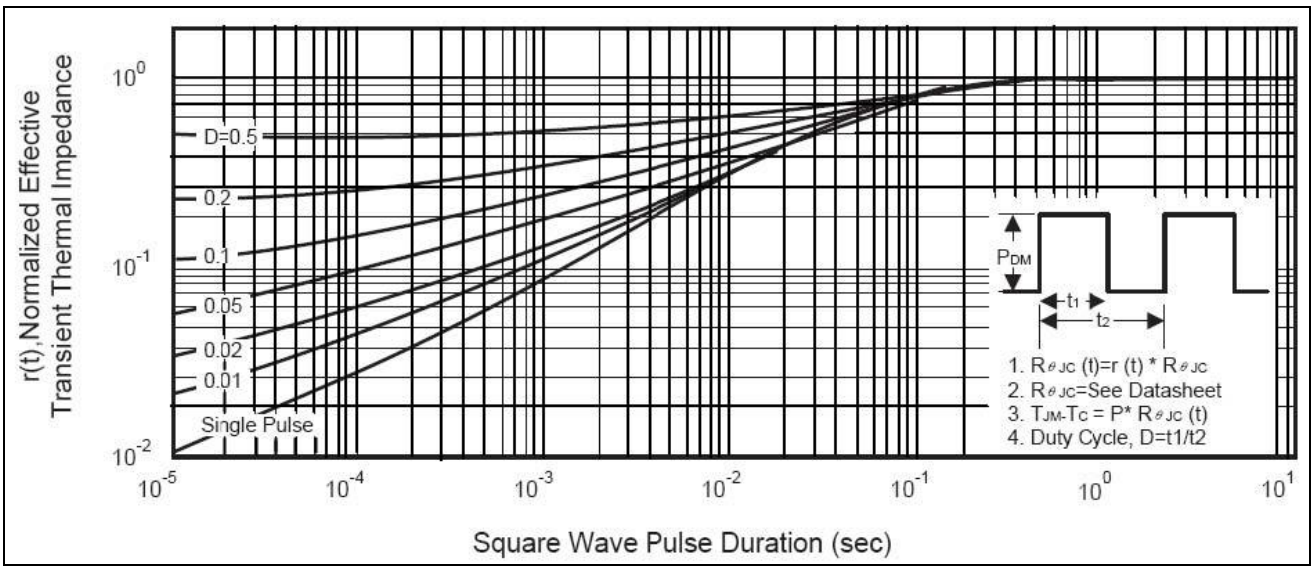
Source-Drain Diode Forward Voltage



Safe Operation Area

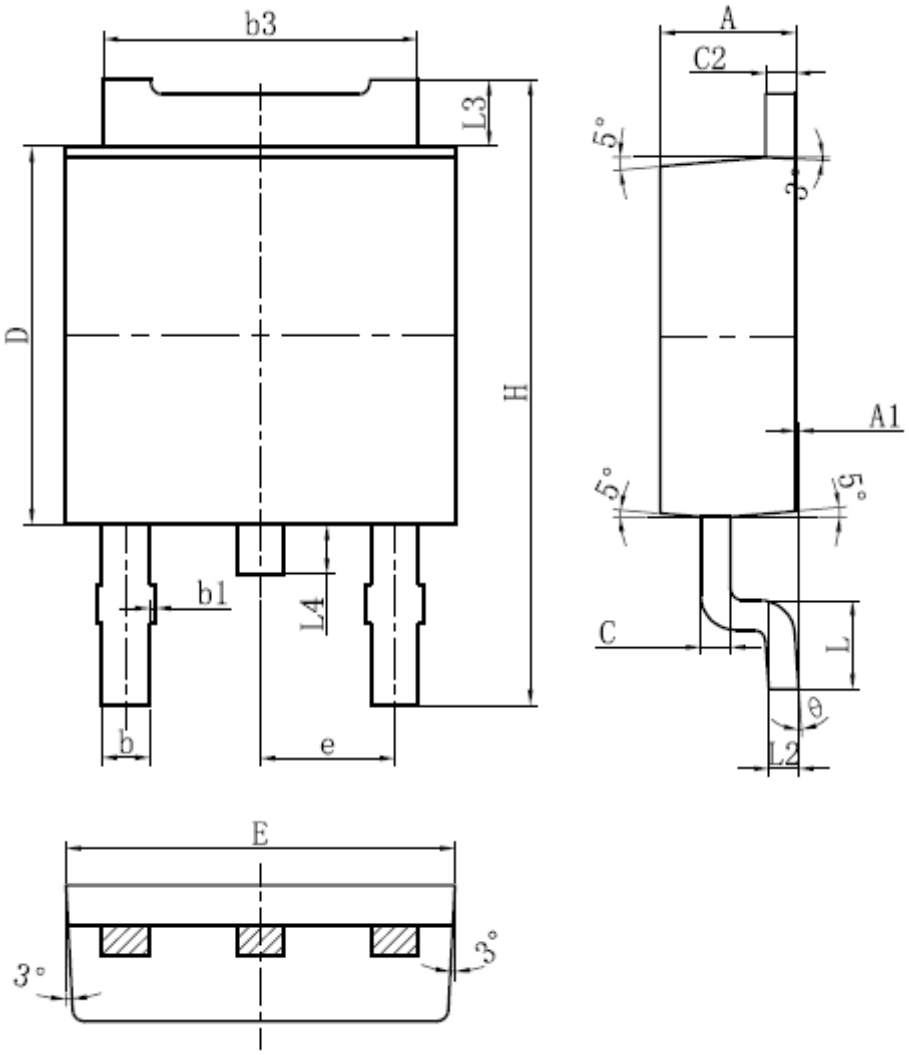


Max Drain Current vs. Junction



Transient Thermal Impedance Curve

DPAK MECHANICAL DATA:



Symbol	Min.	Normal	Max.
E	6.55	6.6	6.65
L	1.40	1.5	1.60
L2	-	0.51BSC	-
L3	0.93	1.08	1.23
L4	0.7	0.8	0.9
D	6.05	6.1	6.15
H	9.9	10.1	10.3
b	0.763	0.813	0.863
b1	0	-	0.1
b3	5.28	5.33	5.38
e	2.23	2.28	2.33
A	2.25	2.3	2.35
A1	0	0.05	0.10
C	0.498	0.508	0.518
C2	0.498	0.508	0.518
θ	0	-	8°

NOTE:
1.Package body size exclude flash and gate burrs.
2.Dimension L is measured in gage plane.
3.Tolerance 0.10mm unless otherwise specified.
4.Controlling dimension is millimeter.Converted inch dimension are not necessarily exact.